**Canadian Materials Diffraction Workshop 2023 (CMDW)**

**Registration Form**

*In-person workshop – Hamilton, Canada July 11 – 14, 2023*

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| **First name**  | Click or tap here to enter text. |
| **Last name**  | Click or tap here to enter text. |
| **Department** | Click or tap here to enter text. |
| **Organization**  | Click or tap here to enter text. |
| **Organization’s Address**  | Click or tap here to enter text. |
| **Your e-mail address**  | Click or tap here to enter text. |
| **Degree** (in progress; MSc or PhD − please indicate degree and years into or past the degree) | Click or tap here to enter text. |
| **Research area** (enter 3 keywords/phrases) | 1. Click or tap here to enter text.2. Click or tap here to enter text.3. Click or tap here to enter text. |
| **Name, e-mail of your supervisor** | Click or tap here to enter text. |
| **Affiliation**  | [ ]  Academic (registration fee $250 CAD per person) [ ]  Non-academic (registration fee $500 CAD per person)  |
| **Instructions for submission:** Please fill out this form and send it to jarvisvm@mcmaster.ca (Vicky Jarvis) as soon as possible to ensure a spot in the workshop. Use the subject line “CMDW 2023 registration” in your e-mail. **Registration deadline is July 1st, 2023.** If there is still space available after the deadline, late registrations will be considered. Please do not send funds for registration until you have been notified of acceptance. Upon acceptance, instructions for payment will be sent to you.  |

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| **Motivation** Describe below your reasons for taking the course and how X-ray crystallography will help you in your research. Describe your current crystallography training and experience. This information will help us fine-tune the workshop.  |
| Click or tap here to enter text. |
| **Software experience** (indicate crystallographic software you have used and your experience level with it) | **List software used and experience** (use 0-10; with 10 being expert). Eg. Diffrac.EVA - 10, SmartlabStudio - 8, TOPAS - 1, GADDS- 2, etc Click or tap here to enter text. |
| **Topics of Interest\***Indicate priority 1, 2, 3… (1 for highest priority). Leave low priority items blank.  |
| Phase Identification  | enter text |
| Texture Analysis  | enter text |
| High Resolution Diffraction | enter text |
| Reciprocal Space Mapping  | enter text |
| X-Ray Reflectivity | enter text |
| Residual Stress Analysis | enter text |
| Non-ambient/In situ/Operando Conditions | enter text |
| % Crystallinity, amorphous content | enter text |
| Other topic(s) – please specify: Click or tap here to enter text.  |

*\*This will help the instructors understand which topics to prepare for and highlight in discussions and tutorials.*